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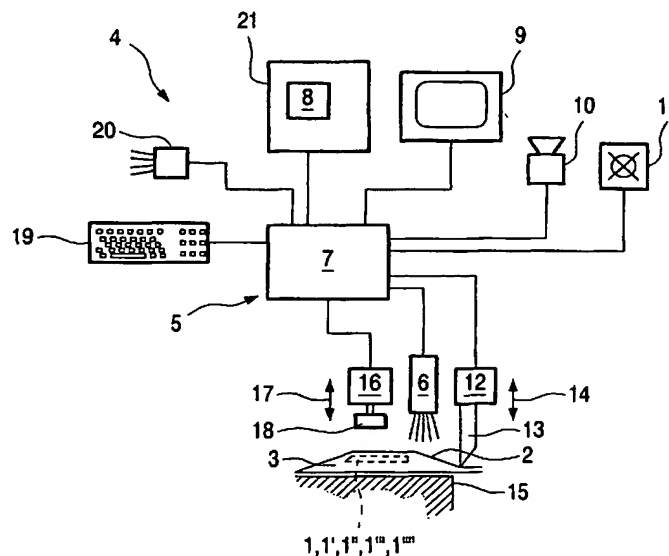
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**(54) Title:** APTITUDE TEST SYSTEM



(57) **Abstract:** The present invention relates to an aptitude test system (4) which includes at least one object (1) which is provided with a data carrier (2) on which data associated with the object (1) is stored, as well as a test device (5) which includes a reading apparatus (6) whereby the data of the data carrier (2) can be transferred to a computer (7). The data includes aptitude data which characterizes at least one permissible application for the associated object (1). The computer (7) has access to current application data which characterizes a concrete application intended for the relevant object (1). For aptitude testing of the relevant object (1) the computer evaluates the aptitude data thereof and the actual application data. The computer (7) outputs a release signal when the object (1) is suitable for the intended application.

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